



# SLOVENSKI STANDARD SIST EN ISO 20339:2017

01-julij-2017

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**Neporušitvene preiskave - Oprema za preiskave z vrtinčnimi tokovi - Značilnosti vrste sonde in preverjanje (ISO 20339:2017)**

Non-destructive testing - Equipment for eddy current examination - Array probe characteristics and verification (ISO 20339:2017)

Zerstörungsfrei Prüfung - Ausrüstung zur Wirbelstromprüfung - Array-Prüfkopfeigenschaften und Überprüfung (ISO 20339:2017)

Essais non destructifs - Appareillage pour examen par courants de Foucault - Caractéristiques des capteurs multiéléments et vérifications (ISO 20339:2017)

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**Ta slovenski standard je istoveten z: EN ISO 20339:2017**

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**ICS:**

19.100          Neporušitveno preskušanje          Non-destructive testing

**SIST EN ISO 20339:2017**

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EUROPEAN STANDARD  
 NORME EUROPÉENNE  
 EUROPÄISCHE NORM

**EN ISO 20339**

April 2017

ICS 19.100

English Version

**Non-destructive testing - Equipment for eddy current  
 examination - Array probe characteristics and verification  
 (ISO 20339:2017)**

Essais non destructifs - Appareillage pour examen par courants de Foucault - Caractéristiques des capteurs multiéléments et vérifications (ISO 20339:2017)

Zerstörungsfreie Prüfung - Technische Ausrüstung für die Wirbelstromprüfung - Kenngrößen von Sensorarrays und deren Verifizierung (ISO 20339:2017)

This European Standard was approved by CEN on 5 February 2017.

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 COMITÉ EUROPÉEN DE NORMALISATION  
 EUROPÄISCHES KOMITEE FÜR NORMUNG

**CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels**

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## European foreword

This document (EN ISO 20339:2017) has been prepared by Technical Committee ISO/TC 135 "Non-destructive testing" in collaboration with Technical Committee CEN/TC 138 "Non-destructive testing" the secretariat of which is held by AFNOR.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by October 2017, and conflicting national standards shall be withdrawn at the latest by October 2017.

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for eddy current examination — Array  
probe characteristics and verification**

*Essais non destructifs — Appareillage pour examen par courants  
de Foucault — Caractéristiques des capteurs multiéléments et  
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## Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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This document was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 4, *Eddy current testing*.

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